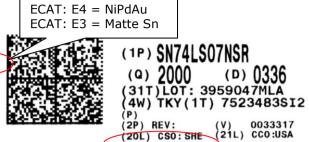
PCN Number:				20180807002.1			PCI	PCN Date: Aug 9, 2018			9, 2018		
Title: Qualification			cation o	of UTAC Thailand as additional Assemb			ibly and	and Test Site for Select Devices					
Customer Contact:			ct:	PCN Manager			Dept:		Quality Services				
Proposed 1 st Ship Date			ip Date				_	stimated Sample Date Provided at Availability: Sample request					
Cha	Change Type:						•						
\boxtimes	Asser	nbly Sit	te		Design				Wafer Bump Site				
		nbly Pro				Data Sheet				Wafer Bump Material			
		nbly Ma			Part number		er change			1	Wafer Bump Process		
			Specifica			Test Site							b Site
Ш	Packi	ng/Ship	ping/La	beling	Ш	Test Process				Wafer Fab Materials			
						DOM D					Wa	ter Fa	b Process
						PCN Deta	IIIS						
Des	cription	on of C	hange:										
Asse	embly a	and Tes	st Site fo	r Select D	evices	e the qualific s listed in the re as follows.	"Produ						
	Assei	mbly Sit	e Ass	sembly Site	Origi	n Assembly	y Countr	y Code			Ass	embly	Site City
	TI	Clark		QAB			PHL					s City	, Pampanga
	UTAC	Thailar	nd	NSE			THA			Bangkok			jkok
Mat	erial [Differe	nces:			TI Clark		UTAC	СТ	'ha	ilan	d	
			Lead fin	ish	NiPdAu			Mat		tte Sn			
			Wire typ			Au				Cu			
			Mount compound		4207123					0138			
			mpound		4208625	4208625		CZ0351					
Upon expiration of this PCN, TI will combine lead free solutions in a single <u>standard part</u> <u>number</u> , for example; <u>SN1602018RVFR</u> – can ship with both Matte Sn and NiPdAu. When available customers may specify NiPdAu finish by ordering the part with the E4 suffix, e.g. <u>SN1602018RVFRE4.</u> " Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.													
Reason for Change:													
Continuity of Supply													
Anticipated impact on Material Declaration													
			Act to the I Declaration Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the TI Eco-Info website. There is no impact to the material meeting current regulatory compliance requirements with this PCN change.										
Ant	Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):												
Non	None												
Cha	Changes to product identification resulting from this PCN:												

Assembly Site					
TI Clark Philippines	Assembly Site Origin (22L)	ASO: QAB	ECAT: E4		
UTAC Thailand	Assembly Site Origin (22L)	ASO: NSE	ECAT: E3		

Sample product shipping label (not actual product label)



(20L) CSO: SHE (22L) ASO: MLA

23L) ACO: MYS

OPT: ITEM: (L)T0:1750

MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

Product Affected:

SN1602018RVFR	TPS544C24RVFR	TPS546C20RVFR	TPS548B22RVFR
SN1602018RVFT	TPS544C24RVFT	TPS546C20RVFT	TPS548B22RVFT
TPS544B24RVFR	TPS546C20ARVFR	TPS546C23RVFR	TPS549B22RVFR
TPS544B24RVFT	TPS546C20ARVFT	TPS546C23RVFT	TPS549B22RVFT

Qualification Report Offload of Power Stage Clip QFN Devices from TI Clark to UTL1 (UTAC) - Phase 2

Approve Date 31-Jul-2018

Product Attributes

Attributes	Qual Device: TPS544C24RVFR		
Assembly Site	UTAC 1 THAILAND		
Package Family	LQFN-CLIP; 7 X 5 (MM)		
Flammability Rating	UL 94 V-0		
Wafer Fab Supplier	CFAB, CFAB, MIHO 8		
Wafer Process	HS FET, LS FET, LBC7		

- Qual Device TPS544C24RVFR is qualified at LEVEL2-260CX.
- Device TPS544C24RVFR contains multiple dies.

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TPS544C24RVFR
-	Drift Analysis, 25C		Pass
AC	Autoclave, 121C	96 Hours	3/231/0
BLR	BLR - Temp Cycle (QFN), - 40C/125C	1000 Cycles	Pass
BHAST	Biased HAST, 110C/85%RH	264 Hours	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	Pass

CDM	ESD CDM	1000V	3/9/0
HBM	ESD HBM	2500V	3/9/0
HTSL	High Temp. Storage Life, 170C	420 Hours	3/231/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass
MSL	Thermal Integrity Sequence	Level 2 - 260C	3/36/0
PC	Preconditioning	Level 2 - 260C	3/924/0
SD	Solderability	Pb-Free	Pass
TC	Temperature Cycle, -55C/125C	700 Cycles	3/231/0

⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable.

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com

⁻ The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1000 Hours, and 170C/420 Hours.

⁻ The following are equivalent Temperature Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles. Quality and Environmental data is available at TI's external Web site: http://www.ti.com/